

FORM PTO-1449				Docket Number (Optional) Application Number						
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143 A	(Use several sheets if necessary)			April 30, 2001		3723				
TRANS		U	. S. PATEN	T DOCUMENTS		<del></del> .				
EXAMINER INITIAL	DOCUMENT NUMBER	DATE		NAME	CLAS	S SUBCLASS	FILING D			
	3,170,273	2/23/65	Walsh et al.							
	3,527,028	9/26/67	Dona	ld R. Oswald		RECF	VEC	<u> </u>		
	4,050,954	9/27/77	Jag	tar S. Basi			<del>  V  </del>			
	4,169,337	10/2/79	Charles C. Payne			AUG 3	2001			
'/	4,304,575	12/8/81	Charles C. Payne		1	TECHNOLOGY CENTER R		)0		
	4,462,188	07/31/84	Char	les C. Payne						
	5,139,571	08/18/92	D	eal et al.						
	5,230,833	07/27/93	Rom	berger et al.						
	5,246,624	9/21/93	M	iller et al.						
	5,314,843	05/24/94	<b>.</b>	Yu et al.						
	5,340,370	08/23/94	Ca	dien et al.			•			
FOREIGN PATENT DOCUMENTS										
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	OTHER	DOCUM	IENTS (includ	ing Author, Title, Date, Per	tinent Page:	s, Etc.)				
			_	opper in Glycerol edings, 1996), Ku		•	erials onth			
/	"Chamical Mask	onical Da	diahina of C	onnor with Owide	and Dat	umar Intaria	<u> </u>			
	"Chemical-Mechanical Polishing of Copper with Oxide and Polymer Interlevel Dielectrics" (Thin Solid Films, 1995), Gutman et al.									
Dielectrice (Time Cond Time, 1999), Carrient et al.						, -0, -1, -1				
	"Stabilization of Alumina Slurry for Chemical-Mechanical Polishing of Copper" (Langmuri, 1996) Lou et al. (~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~									
EXAMINER				DATE CONSIDERED						
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citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.										

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## INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

	Docket Number (Optional)	Application Number
	341.6910USU	09/845,549
i	Applicant	
	Pasqualoni et al.	
	Filing Date	Group Art Unit
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## U. S. PATENT DOCUMENTS TE NAME CLASS SUBCLASS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	5,607,718	3/4/97	Sasaki et al.				
	5,656,097	8/12/97	Olesen et al.		RECE	MED	
	5,695,384	12/9/97	Howard R. Beratan			VED	
	5,750,440	5/12/98	Vanell et al.		AUG 3	2001	
	5,770,095	6/23/98	Sasaki et al.	TEC	HNOLOGY CE	UTED DOZGO	
	5,908,509	6/1/99	Olesen et al.			+ <del>-n no/00</del>	
	5,954,997	9/21/99	Kaufman et al.				
	5,980,775	11/9/99	Grumbine et al.				
	5,993,685	11/30/99	Currie et al.				
	5,996,595	12/7/99	Olesen et al.				
	6,010,962	1/4/00	Liu et al.				
EODEICNI DATENT DOCUMENTO							

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Trans YES	NO
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## OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

"Initial Study on Copper MCP Slurry Chemistries" (Thin Solid Films, 1995) Carpio et al.

(a month)

"Chemical-Mechanical Polishing of Copper for Interconnect Formation" (Microelectronic Engineering, 1997) Stavreva et al. ( month)

"Development of a 1:1:1 Slurry for Tantalum Layer Polishing" in proceedings of the CMP-MIC conference, February 1999

**EXAMINER** 

DATE CONSIDERED

12/4/02

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.